

MBM250H33E3

Silicon N-channel IGBT 3300V E3 version

FEATURES

- * Soft switching behavior & low conduction loss:
Soft low-injection punch-through High conductivity IGBT.
- * Low driving power due to low input capacitance MOS gate.
- * Low noise recovery: Ultra soft fast recovery diode.

ABSOLUTE MAXIMUM RATINGS (Tc=25°C)

Item	Symbol	Unit	MBM250H33E3
Collector Emitter Voltage	V _{CES}	V	3,300
Gate Emitter Voltage	V _{GES}	V	±20
Collector Current	DC	I _c	250 (Tc=95 °C)
	1ms	I _{cp}	
Forward Current	DC	I _F	250
	1ms	I _{FM}	500
Peak Forward Surge Current	I _{FSM}	A _p	2000
Total Power Dissipation	P _{tot}	W	2500 (Tc=25°C per IGBT)
Junction Temperature	T _j	°C	-40 ~ +150
Junction Operating Temperature	T _{jop}	°C	-40 ~ +125
Case Temperature	T _c	°C	-40 ~ +125
Storage Temperature	T _{stg}	°C	-50 ~ +125
Isolation Voltage	V _{ISO}	V _{RMS}	7,700 (AC 1 minute)
Screw Torque	Mounting (M6)	-	6 (1)

Notes: (1) Recommended Value 5.5±0.5N·m

- * Please contact our representatives at order.
- * For improvement, specifications are subject to change without notice.
- * For actual application, please confirm this spec sheet is the newest revision.

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ELECTRICAL CHARACTERISTICS (IGBT)

Item	Symbol	Unit	Min.	Typ.	Max.	Test Conditions		
Collector Emitter Cut-Off Current	I_{CES}	mA	-	-	2	$T_j=25^\circ\text{C}$	$V_{CE}=3,300\text{V}, V_{GE}=0\text{V}$	
			-	4	10	$T_j=125^\circ\text{C}$		
Gate Emitter Leakage Current	I_{GES}	nA	-500	-	+500	$V_{GE}=\pm 20\text{V}, V_{CE}=0\text{V}, T_j=25^\circ\text{C}$		
Collector Emitter Saturation Voltage	$V_{CE(sat)}$	V	-	2.65	-	$T_j=25^\circ\text{C}$	$I_C=250\text{A}, V_{GE}=15\text{V}$	
			2.70	3.40	3.90	$T_j=125^\circ\text{C}$		
			-	3.60	-	$T_j=150^\circ\text{C}$		
Gate Emitter Threshold Voltage	$V_{GE(TH)}$	V	5.5	6.3	7.5	$V_{CE}=10\text{V}, I_C=250\text{mA}, T_j=25^\circ\text{C}$		
Gate Charge	Q_g	μC	-	2.8	-	$V_{CC}=2800\text{V}, I_C=250\text{A}, V_{GE}=\pm 15\text{V}$		
Input Capacitance	C_{ies}	nF	-	33	-	$V_{CE}=10\text{V}, V_{GE}=0\text{V}, f=100\text{kHz}, T_j=25^\circ\text{C}$		
Output Capacitance	C_{oes}	nF	-	3.3	-			
Reverse transfer capacitance	C_{res}	nF	-	2.3	-			
Internal Gate Resistance	R_{ge}	Ω	-	5.4	-	$V_{CE}=10\text{V}, V_{GE}=0\text{V}, f=100\text{kHz}, T_j=25^\circ\text{C}$		
Switching Times	Rise Time	t_r	μs	-	1.5	-	$T_j=25^\circ\text{C}$	$V_{CC}=1,800\text{V}, I_C=250\text{A}, L_s=400\text{nH}, R_G=15\Omega (2), V_{GE}=\pm 15\text{V}$
				-	1.8	2.5	$T_j=125^\circ\text{C}$	
				-	1.9	-	$T_j=150^\circ\text{C}$	
	Turn On Time	t_{on}		-	2.1	-	$T_j=25^\circ\text{C}$	
				-	2.5	3.3	$T_j=125^\circ\text{C}$	
				-	2.5	-	$T_j=150^\circ\text{C}$	
	Fall Time	t_f		-	1.6	-	$T_j=25^\circ\text{C}$	
				-	1.9	3.2	$T_j=125^\circ\text{C}$	
				-	1.9	-	$T_j=150^\circ\text{C}$	
	Turn Off Time	t_{off}		-	3.6	-	$T_j=25^\circ\text{C}$	
				-	4.0	5.2	$T_j=125^\circ\text{C}$	
				-	4.0	-	$T_j=150^\circ\text{C}$	
Turn On Loss	$E_{on(full)}$	J/p	-	0.35	-	$T_j=25^\circ\text{C}$	$V_{CC}=1800\text{V}, I_C=250\text{A}, L_s=400\text{nH}, R_G=15\Omega (2), V_{GE}=\pm 15\text{V}$	
	$E_{on(10\%)}$		-	0.43	0.58	$T_j=125^\circ\text{C}$		
	$E_{on(full)}$		-	0.48	-	$T_j=125^\circ\text{C}$		
Turn Off Loss	$E_{off(full)}$	-	0.50	-	$T_j=150^\circ\text{C}$			
	$E_{off(full)}$	-	0.40	-	$T_j=25^\circ\text{C}$			
	$E_{off(10\%)}$	-	0.37	0.50	$T_j=125^\circ\text{C}$			
	$E_{off(full)}$	-	0.48	-	$T_j=125^\circ\text{C}$			
	$E_{off(full)}$	-	0.49	-	$T_j=150^\circ\text{C}$			

Notes:(2) R_G value is the test condition's value for evaluation of the switching times, not recommended value.
Please, determine the suitable R_G value after the measurement of switching waveforms (overshoot voltage, etc.) with appliance mounted.

ELECTRICAL CHARACTERISTICS (DIODE)

Item	Symbol	Unit	Min.	Typ.	Max.	Test Conditions	
Peak Forward Voltage Drop	V_{FM}	V	-	2.70	-	$T_j=25^\circ\text{C}$	$I_F=250\text{A}, V_{GE}=0\text{V}$
			2.30	2.90	3.30	$T_j=125^\circ\text{C}$	
			-	2.80	-	$T_j=150^\circ\text{C}$	
Reverse Recovery Time	t_{rr}	μs	-	0.50	-	$T_j=25^\circ\text{C}$	$V_{CC}=1800\text{V}, I_F=250\text{A}, L_s=400\text{nH}, R_G=15\Omega (3)$
			-	0.70	1.2	$T_j=125^\circ\text{C}$	
Reverse Recovery Current	I_{rr}	A	-	270	-	$T_j=25^\circ\text{C}$	
			-	330	-	$T_j=125^\circ\text{C}$	
			-	330	-	$T_j=150^\circ\text{C}$	
Recovery charge	Q_{rr}	μC	-	70	-	$T_j=25^\circ\text{C}$	
			-	120	-	$T_j=125^\circ\text{C}$	
Reverse Recovery Loss	$E_{rr(full)}$	J/p	-	0.21	-	$T_j=25^\circ\text{C}$	
	$E_{rr(10\%)}$		-	0.31	0.41	$T_j=125^\circ\text{C}$	
	$E_{rr(full)}$		-	0.40	-	$T_j=125^\circ\text{C}$	
	$E_{rr(full)}$		-	0.45	-	$T_j=150^\circ\text{C}$	

Notes:(3) R_G value is the test condition's value for evaluation of the switching times, not recommended value.
Please, determine the suitable R_G value after the measurement of switching waveforms (overshoot voltage, etc.) with appliance mounted.

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THERMAL CHARACTERISTICS

Item	Symbol	Unit	Min.	Typ.	Max.	Test Conditions	
Thermal Impedance	IGBT	$R_{th(j-c)}$	K/W	-	-	0.050	Junction to case
	FWD	$R_{th(j-c)}$		-	-	0.100	
Contact Thermal Impedance		$R_{th(c-f)}$	K/W	-	0.032	-	Case to fin ($\lambda_{grease}=1W/(m \cdot K)$, heat-sink flatness $\leq 50\mu m$)

MODULE MECHANICAL CHARACTERISTICS

Item	Unit	Characteristics	Conditions	
Weight	g	840		
Creepage Distance	Between terminal	mm	54	Collector-sense to Emitter-main
	Terminal-Base	mm	64	
Clearance Distance	Between terminal	mm	19	Collector-sense to Emitter-main
	Terminal-Base	mm	35	
Stray inductance in module	LS(CM-EM)	nH	140	Between C1- E2
Resistance, Terminal-chip	R_{CC+EE}	m Ω	1.5	Terminal to chip
Comparative Tracking Index (CTI)			600	
Module base plate Material			Cu	
Baseplate Thickness	mm		5	
Insulation plate Material			AlN	
Terminal Surface treatment			Ni plating	
Case Material			Poly-Phenilene Sulfide	

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DEFINITION OF TEST CIRCUIT

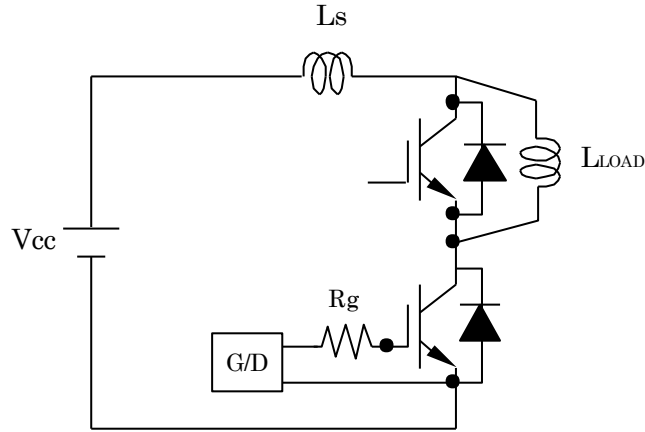


Fig.1 Switching test circuit

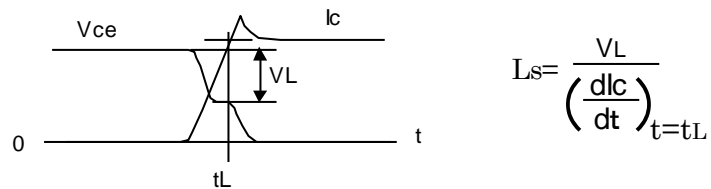


Fig.2 Definition of Ls

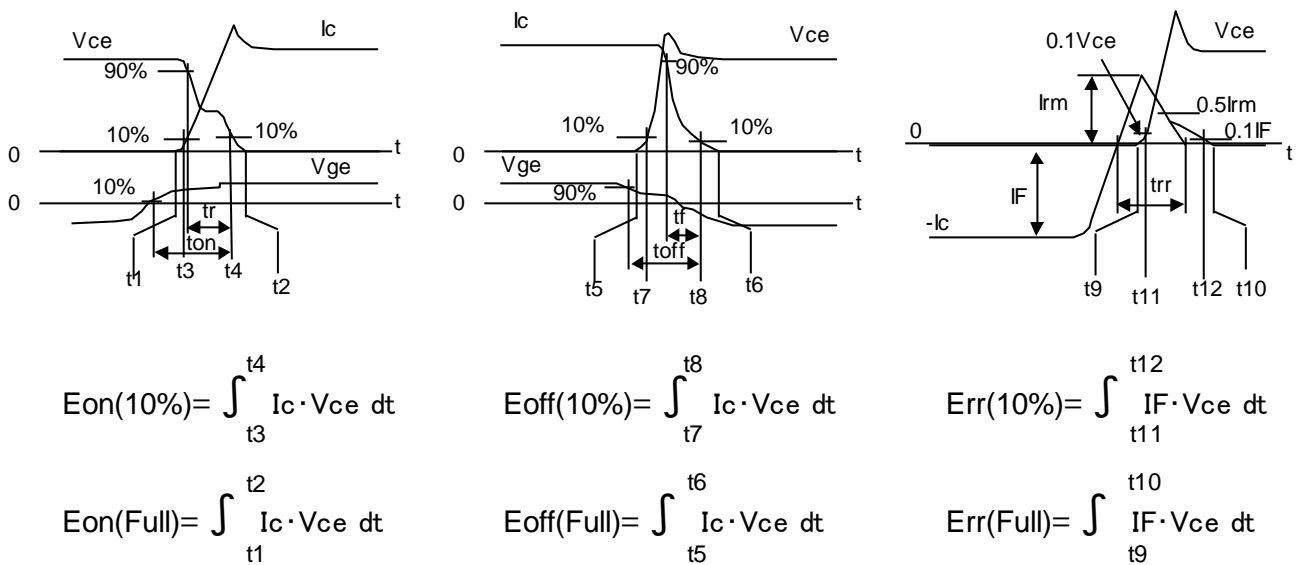
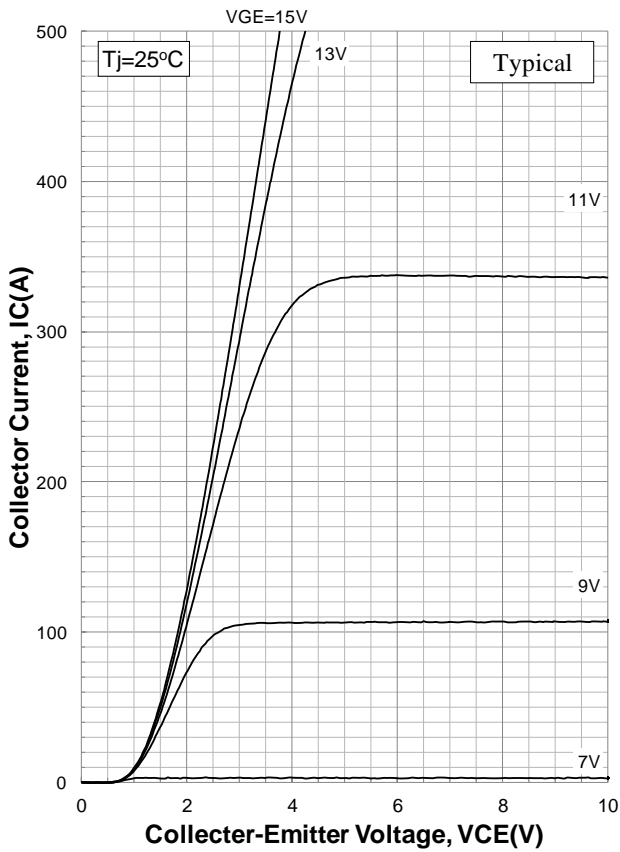


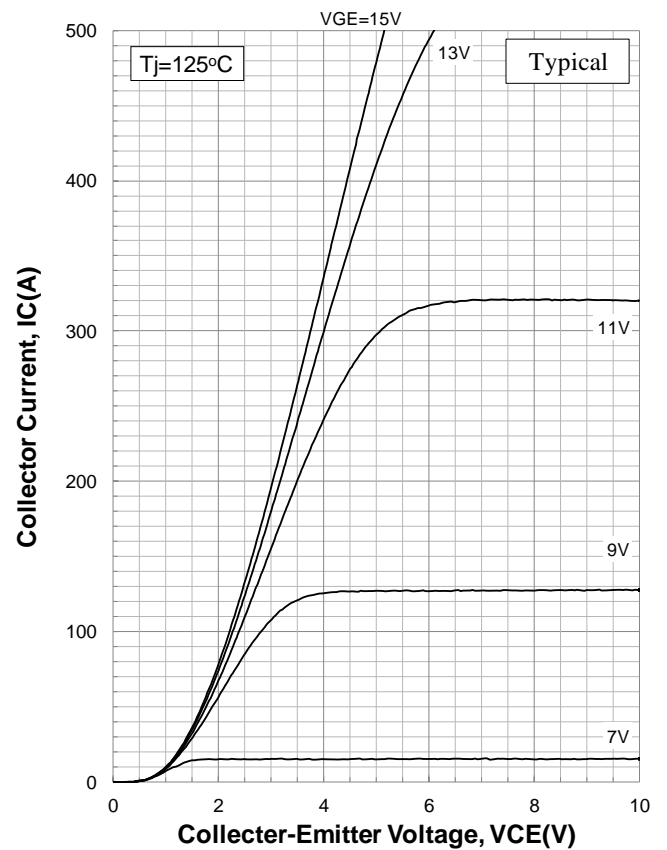
Fig.3 Definition of switching loss

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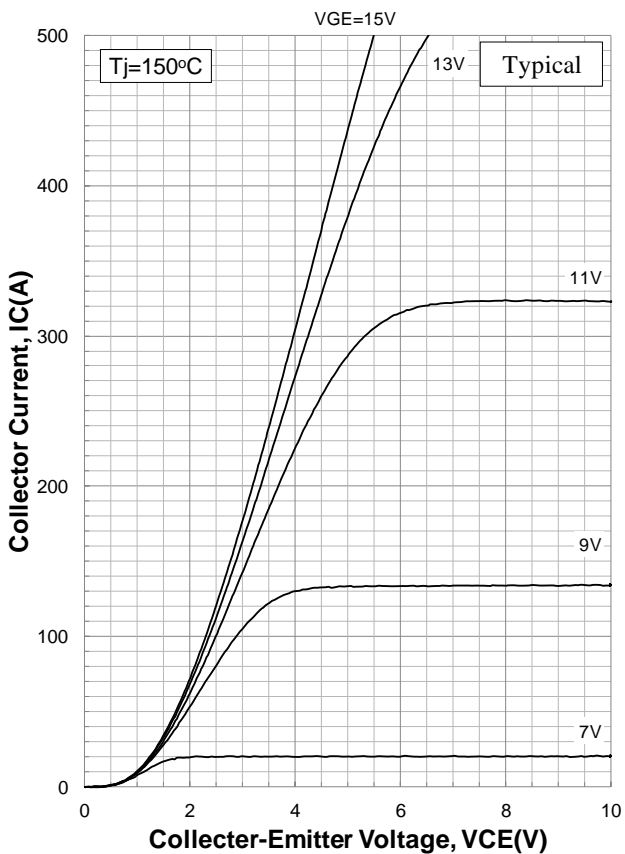
STATIC CHARACTERISTICS



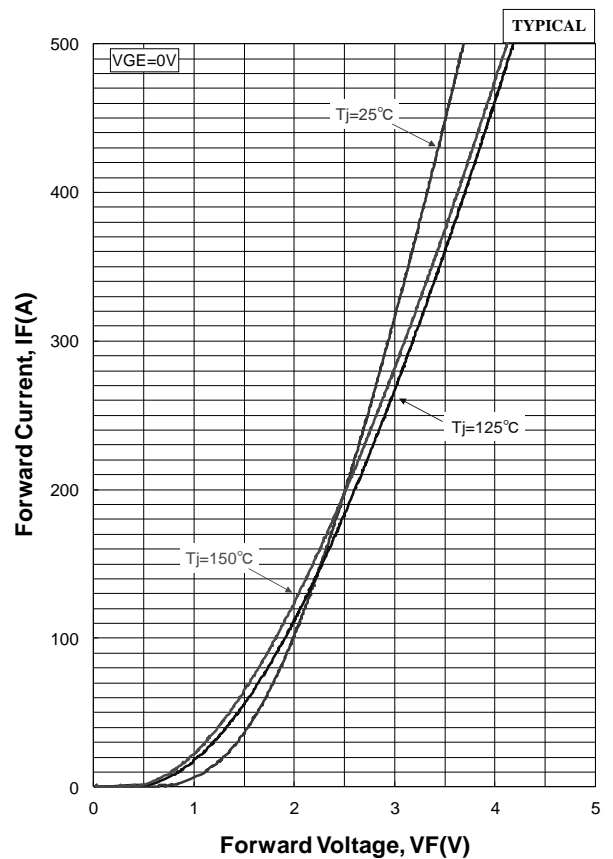
Collector Current vs. Collector to Emitter Voltage



Collector Current vs. Collector to Emitter Voltage



Collector Current vs. Collector to Emitter Voltage

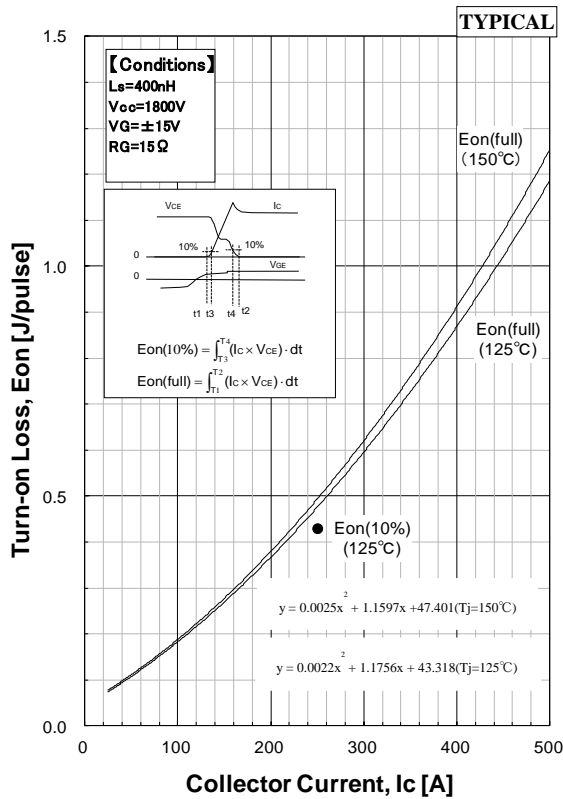


Forward Voltage of free-wheeling diode

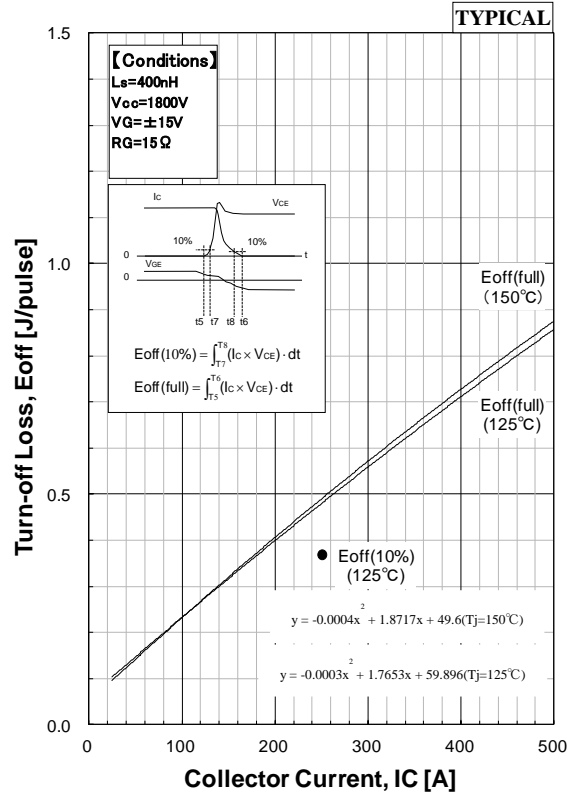
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DYNAMIC CHARACTERISTICS

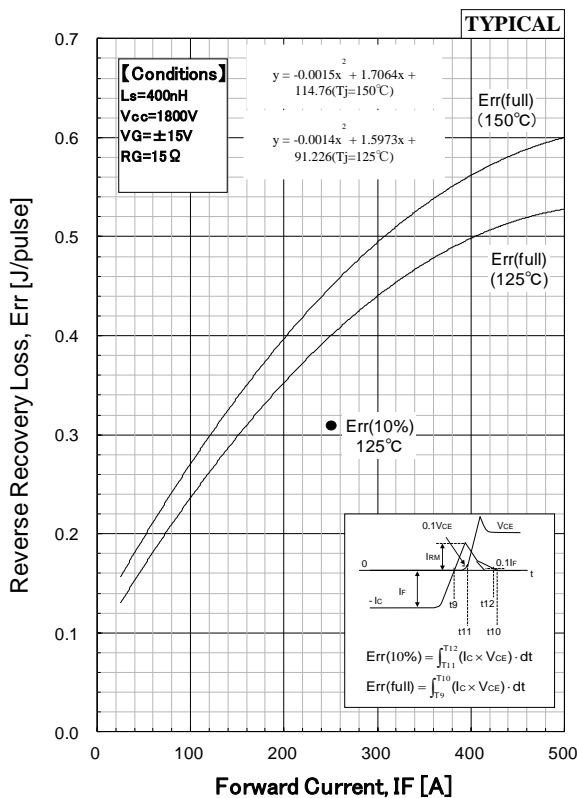
DEPENDENCE OF CURRENT



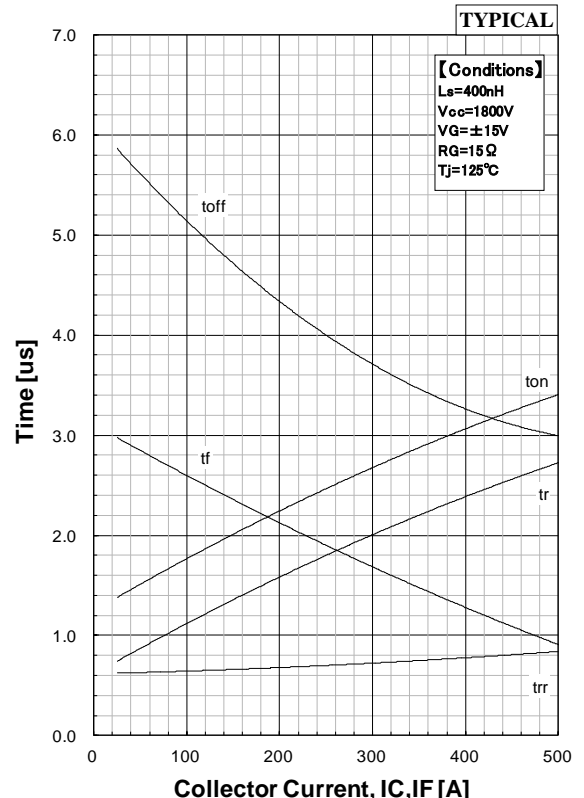
Turn-on Loss vs. Collector current



Turn-off Loss vs. Collector current



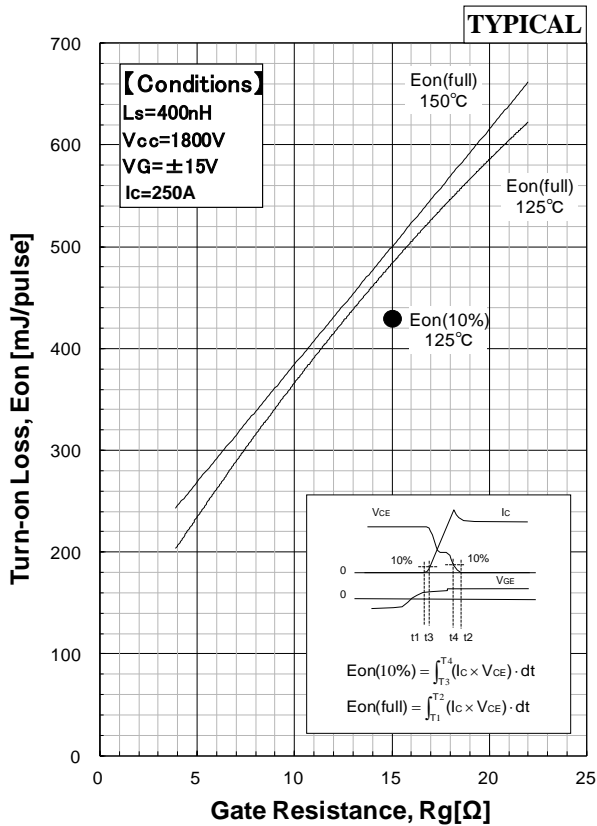
Recovery loss vs. Forward current



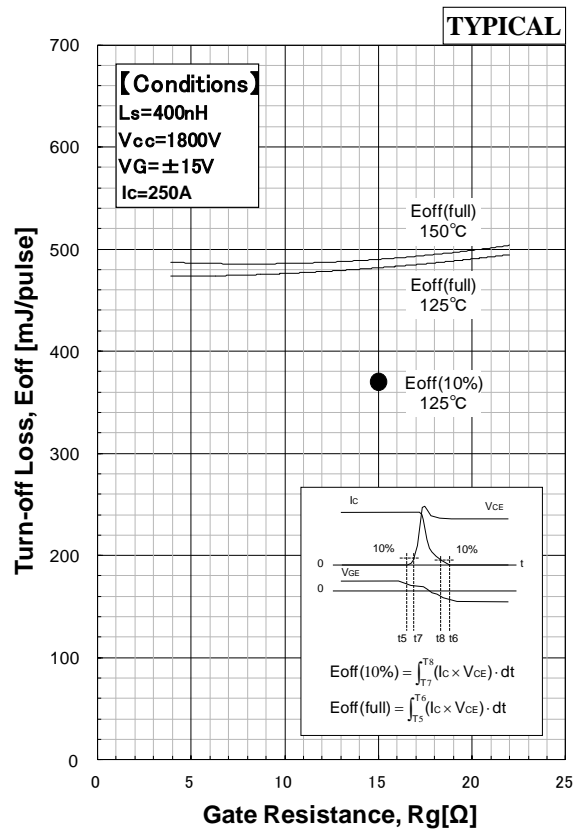
Switching time vs. Collector current

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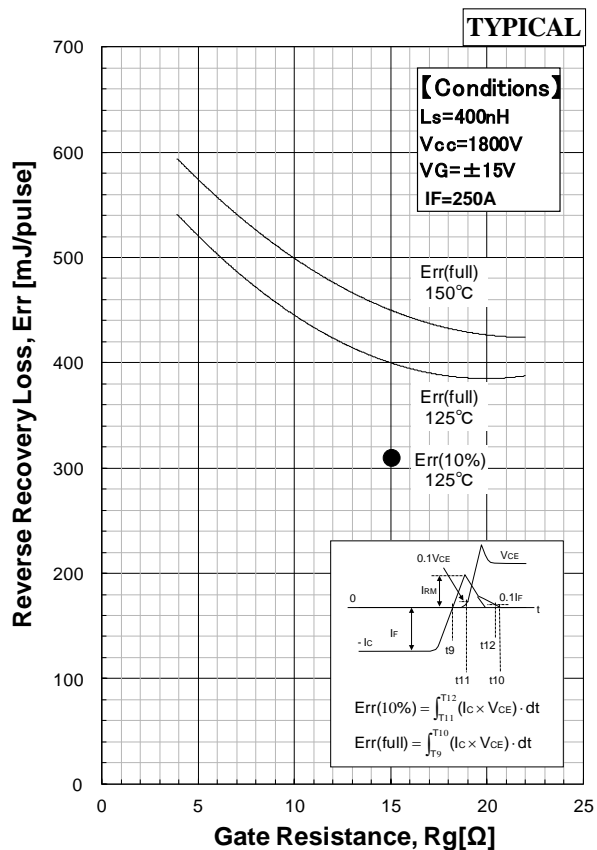
DEPENDENCE OF RG



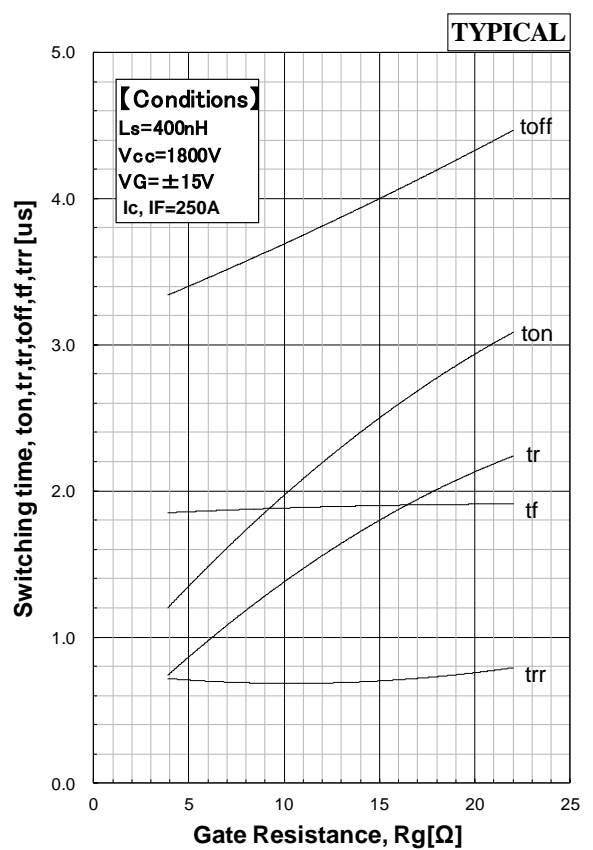
Turn-on Loss vs Gate Resistance



Turn-off Loss vs Gate Resistance



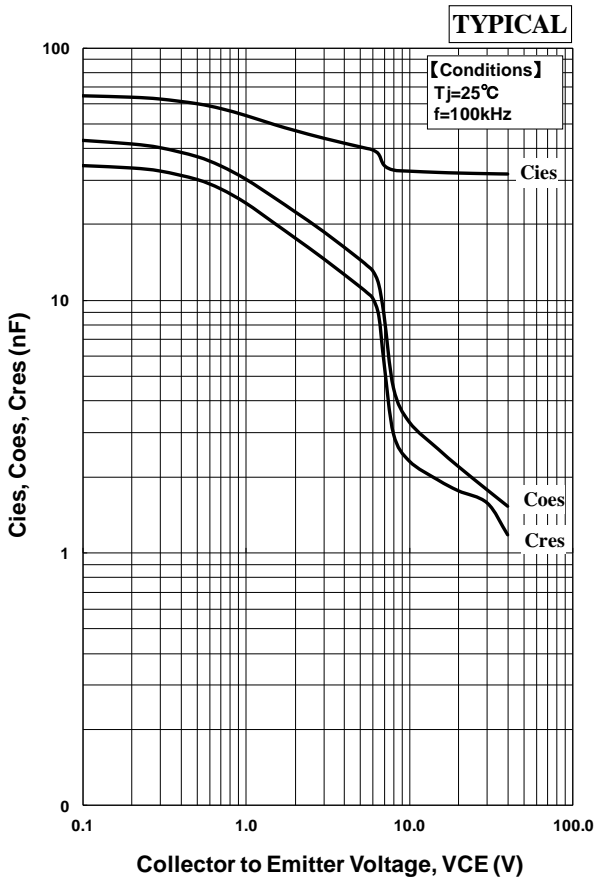
Recovery Loss vs Gate Resistance



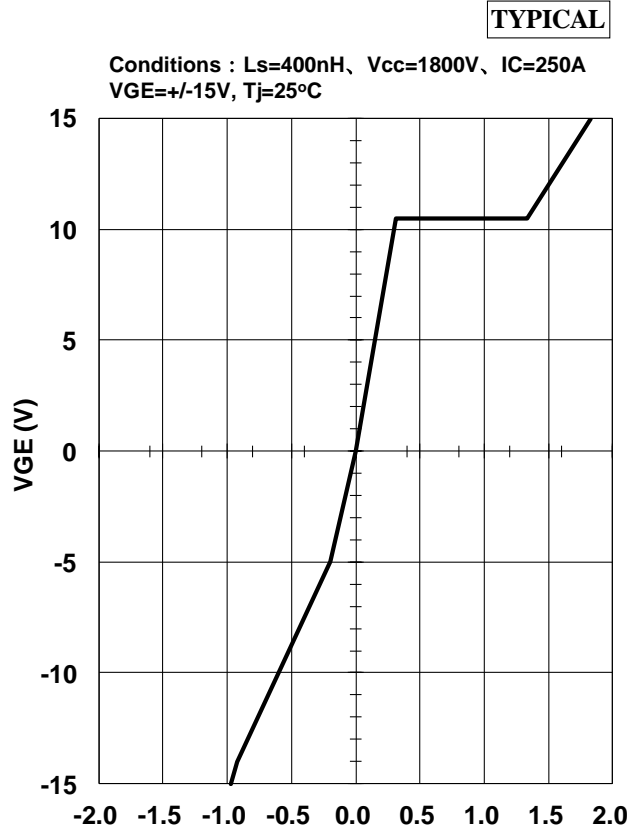
Switching time vs Gate Resistance

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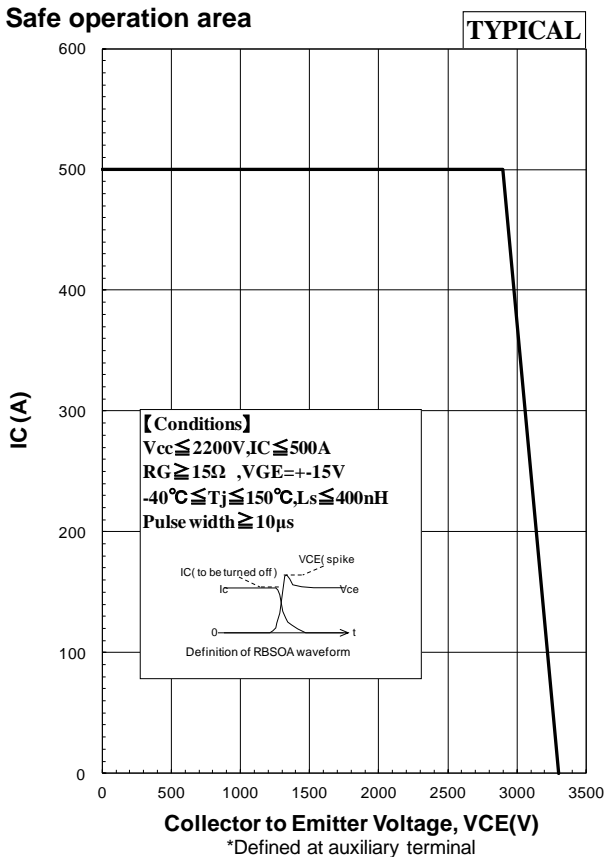
Cies, Coes, Cres-VCE, QG-VG



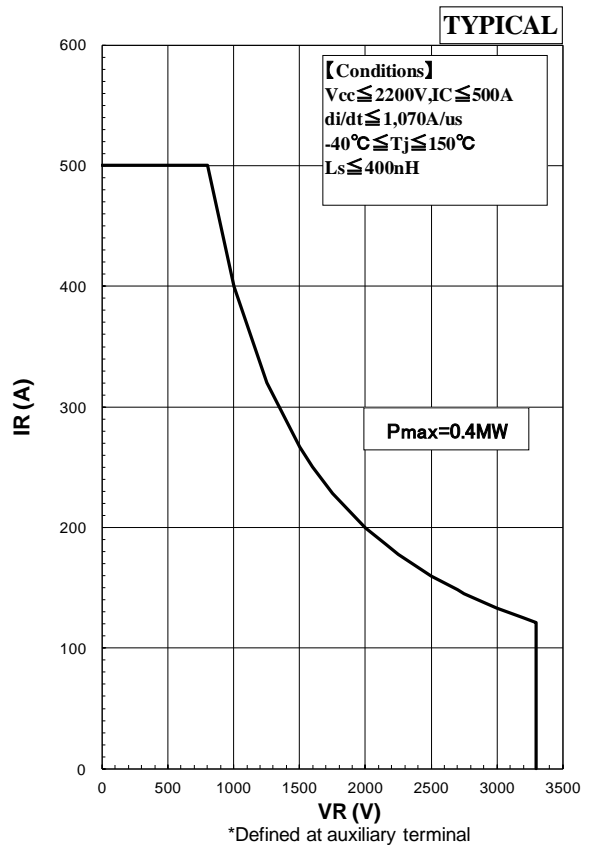
Cies, Coes, Cres-VCE



QG-VGE Curve



Reverse bias Safe operation area (RBSOA)

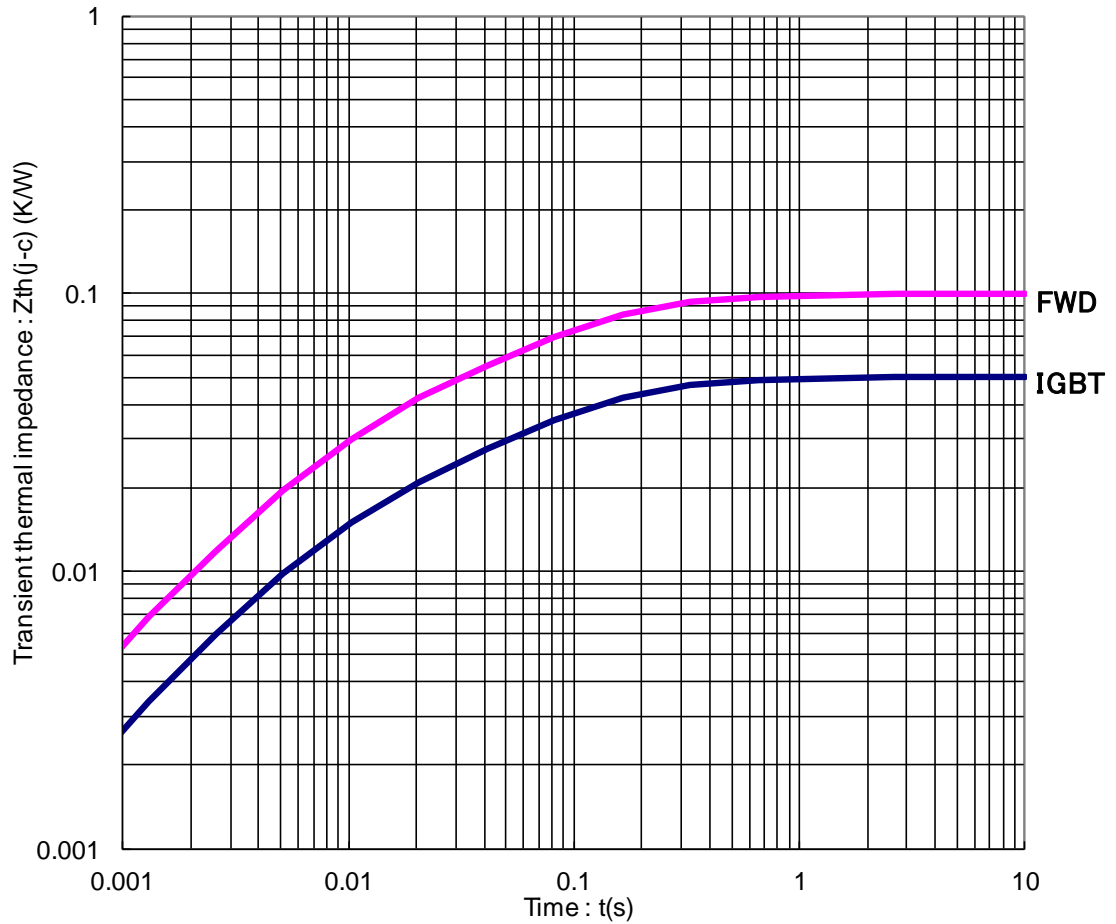


Reverse Recovery Safe operation area (RecSOA)

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TRANSIENT THERMAL IMPEDANCE

Maximum



Transient Thermal Impedance Curve

Curve approximation model
 $Z_{th} = \sum r_{th}[n] * (1 - \exp(-t/\tau_{th}[n]))$

n	1	2	3	4	Unit
$\tau_{th}[n]$	2.73E-01	7.21E-02	8.98E-03	2.02E-03	sec
$r_{th}[n,IGBT]$	9.27E-03	2.52E-02	1.32E-02	2.35E-03	K/W
$r_{th}[n,Diode]$	1.83E-02	5.07E-02	2.61E-02	4.89E-03	K/W

Material Declaration

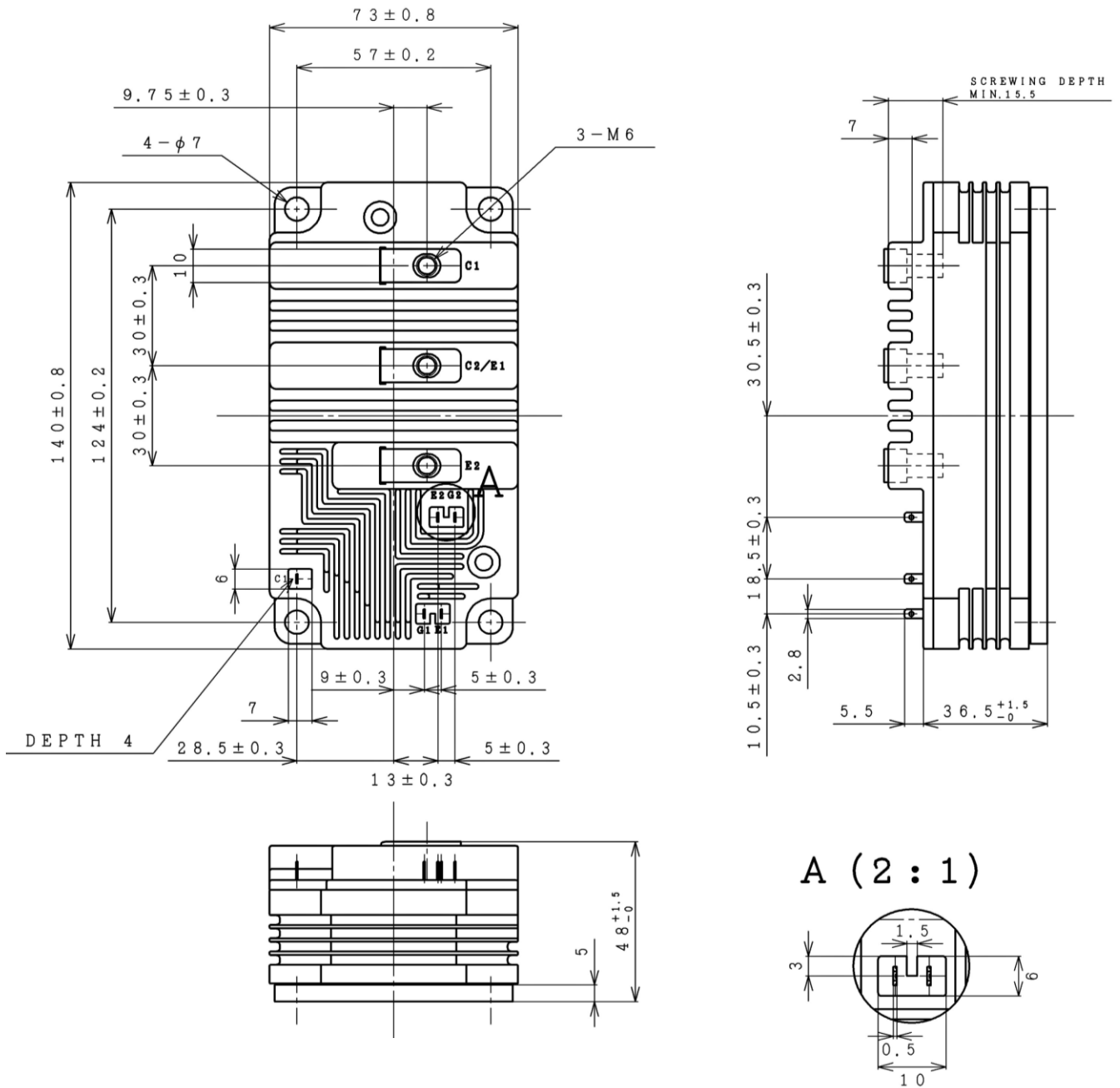
Please note the following material is contained in the product in order to keep product characteristic and reliability level.

Material	Contained part
Lead (Pb) and its compounds	Solder

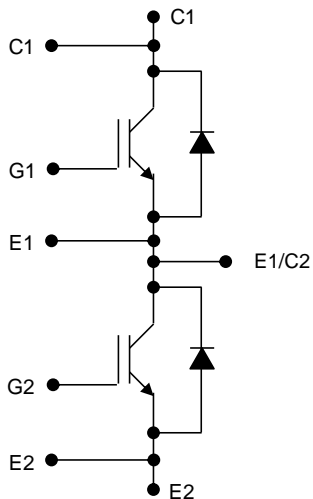
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Module Outline Drawing

Unit: mm



CIRCUIT DIAGRAM



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HITACHI POWER SEMICONDUCTORS

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1. The information given herein, including the specifications and dimensions, is subject to change without prior notice to improve product characteristics. Before ordering, purchasers are advised to contact Hitachi sales department for the latest version of this data sheets.
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